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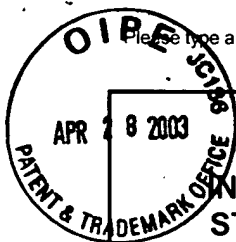
Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	10/040,953
				Filing Date	1/5/02
				First Named Inventor	Steven Teig
				Group Art Unit	2881 2825
				Examiner Name	ANDREA LIU
Sheet	1	of	1	Attorney Docket Number	SPLX.P0024

U.S. PATENT DOCUMENTS						
Examiner* Initials	Cite No.	U.S. Patent Document Number Kind Code* (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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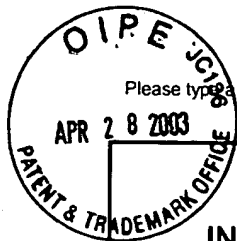
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		Office ³	Number ⁴	Kind Code (if known) ⁵				
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		Examiner Name	ANDREA LIA		
Sheet	4	of	4	Attorney Docket Number	SPLX.P0024

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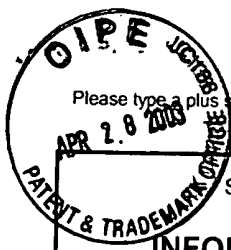
NON PATENT LITERATURE DOCUMENTS

Examiner* Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
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